

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants: Date: October 29, 2008
Beaman et al. Group Art Unit: 2829
Serial No.: 09/382,834 Examiner: V. P. Nguyen
Filed: August 25, 1999 Docket No.: YOR919930028US5
For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND
METHODS OF USE THEREOF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

please enter
10/31/08
/VII/

RESPONSE AFTER FINAL ACTION DATED 05/04/2008 AND
ADVISORY ACTION DATED 10/14/2008

Sir:

In response to the Final Office Action dated 05/04/2008 and Advisory Action dated 10/14/2008, please consider the following.